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((signal sampling<in>metadata) <and> (measuring<in>metadata))

<u>#1</u>

((measurement circuit<in>metadata) <and> (<u>#2</u> elements<in>metadata))

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2/24/06 2:06 PM

EAST Search History								
Ref #	Hits	Search Query	DBs	Defau It Opera tor	Plur als	Time Stamp		
L2	73	disturbance SAME "electric\$ pulse"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/24		
L3	16	disturbance WITH "electric\$ pulse"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWI NT; IBM_T DB	E	ON	2006/02/24 06:29		
L4		3 "external disturband SAME "electric\$ pu	ce" US-PG USPAT USOC ; EPO JPO; DERV NT; IBM_ DB	Γ; R ; VE	ON	2006/02/24		

EAST Search History							
L6	21	"signal sampling" NEAR measuring	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/24 10:06	
L7	376	"signal sampling" WITH measuring	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/24 11:23	
S1	324	324/76.13.ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/23	

	EAST Sedicit filstory							
S2	308	326/104.ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/22 09:06		
S3	345	G01D001/14.ipc.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/02/22 09:07		
S4	1	"20040080343".did.	US-PGP UB	AND	ON	2006/02/23 08:18		
S5	384	elements WITH "measurement circuit"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	OFF	2006/02/24 06:28		

S6	5	((electric OR electronic) NEAR elements) SAME "measurement circuit"	US-PGP UB; USPAT; USOCR	AND	OFF	2006/02/23 08:24
		measurement circuit	; EPO; JPO;			
			DERWE NT; IBM_T			
			DB	,		